

CD4026B, CD4033B Types

CMOS Decade Counters/Dividers

High-Voltage Types (20-Volt Rating)

With Decoded 7-Segment Display Outputs and:

Display Enable – CD4026B

Ripple Blanking – CD4033B

■ CD4026B and CD4033B each consist of a 5-stage Johnson decade counter and an output decoder which converts the Johnson code to a 7-segment decoded output for driving one stage in a numerical display.

These devices are particularly advantageous in display applications where low power dissipation and/or low package count are important.

Inputs common to both types are CLOCK, RESET, & CLOCK INHIBIT; common outputs are CARRY OUT and the seven decoded outputs (a, b, c, d, e, f, g). Additional inputs and outputs for the CD4026B include DISPLAY ENABLE input and DISPLAY ENABLE and UNGATED "C-SEGMENT" outputs. Signals peculiar to the CD4033B are RIPPLE-BLANKING INPUT AND LAMP TEST INPUT and a RIPPLE-BLANKING OUTPUT.

A high RESET signal clears the decade counter to its zero count. The counter is advanced one count at the positive clock signal transition if the CLOCK INHIBIT signal is low. Counter advancement via the clock line is inhibited when the CLOCK INHIBIT signal is high. The CLOCK INHIBIT signal can be used as a negative-edge clock if the clock line is held high. Antilock gating is provided on the JOHNSON counter, thus assuring proper counting sequence. The CARRY-OUT (C_{out}) signal completes one cycle every ten CLOCK INPUT cycles and is used to clock the succeeding decade directly in a multi-decade counting chain.

The seven decoded outputs (a, b, c, d, e, f, g) illuminate the proper segments in a seven

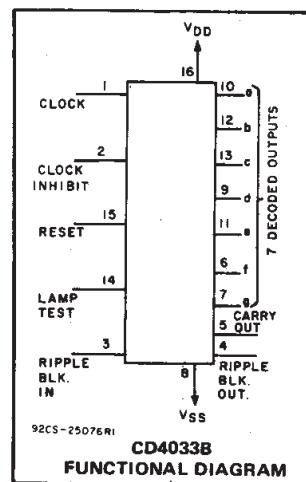
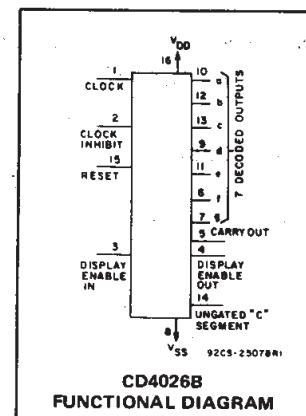
Features:

- Counter and 7-segment decoding in one package
- Easily interfaced with 7-segment display types
- Fully static counter operation: DC to 6 MHz (typ.) at $V_{DD}=10$ V
- Ideal for low-power displays
- Display enable output (CD4026B)
- "Ripple blanking" and lamp test (CD4033B)
- 100% tested for quiescent current at 20 V
- Standardized, symmetrical output characteristics
- 5-V, 10-V, and 15-V parametric ratings
- Schmitt-triggered clock inputs
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

Applications

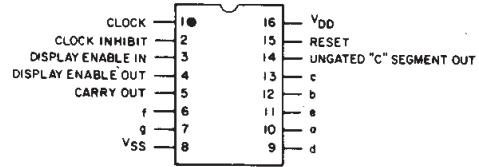
- Decade counting 7-segment decimal display
- Frequency division 7-segment decimal displays
- Clocks, watches, timers (e.g. $\div 60$, $\div 60$, $\div 12$ counter/display)
- Counter/display driver for meter applications

segment display device used for representing the decimal numbers 0 to 9. The 7-segment outputs go high on selection in the CD4033B; in the CD4026B these outputs go high only when the DISPLAY ENABLE IN is high.

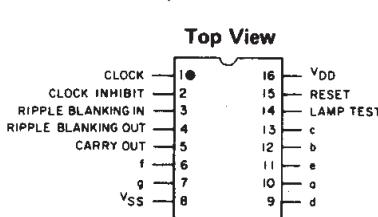


TERMINAL DIAGRAMS

Top View



Top View



MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE RANGE, (V_{DD})

Voltages referenced to V_{SS} Terminal -0.5V to +20V

INPUT VOLTAGE RANGE, ALL INPUTS -0.5V to V_{DD} +0.5V

DC INPUT CURRENT, ANY ONE INPUT ± 10 mA

POWER DISSIPATION PER PACKAGE (P_D):

For $T_A = -55^\circ\text{C}$ to $+100^\circ\text{C}$ 500mW

For $T_A = +100^\circ\text{C}$ to $+125^\circ\text{C}$ Derate Linearity at 12mW/ $^\circ\text{C}$ to 200mW

DEVICE DISSIPATION PER OUTPUT TRANSISTOR

FOR $T_A = \text{FULL PACKAGE-TEMPERATURE RANGE (All Package Types)}$ 100mW

OPERATING-TEMPERATURE RANGE (T_A) -55°C to $+125^\circ\text{C}$

STORAGE TEMPERATURE RANGE (T_{stg}) -65°C to $+150^\circ\text{C}$

LEAD TEMPERATURE (DURING SOLDERING):

At distance $1/16 \pm 1/32$ inch (1.59 ± 0.79 mm) from case for 10s max $+265^\circ\text{C}$

CD4026B, CD4033B Types

RECOMMENDED OPERATING CONDITIONS

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	V _{DD} (V)	LIMITS		UNITS	
		MIN.	MAX.		
Supply-Voltage Range (For T _A = Full Package Temperature Range)		3	18	V	
Clock Input Frequency, f _{CL}	5	—	2.5	MHz	
	10	—	5.5		
	15	—	8		
Clock Pulse Width, t _{WCL}	5	220	—	ns	
	10	100	—		
	15	80	—		
Clock Rise and Fall Time, t _{fCL-fCL}	5	—	Unlimited		
	10	—			
	15	—			
Clock Inhibit Set Up Time, t _{SU}	5	200	—		
	10	50	—		
	15	30	—		
Reset Pulse Width, t _R	5	200	—		
	10	100	—		
	15	50	—		
Reset Removal Time	5	30	—		
	10	15	—		
	15	10	—		

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)							UNITS	
	V _O (V)	V _{IN} (V)	V _{DD} (V)	+25								
				-55	-40	+85	+125	Min.	Typ.	Max.		
Quiescent Device Current, I _{DD} Max.	—	0,5	5	5	5	150	150	—	0.04	5	μA	
	—	0,10	10	10	10	300	300	—	0.04	10		
	—	0,15	15	20	20	600	600	—	0.04	20		
	—	0,20	20	100	100	3000	3000	—	0.08	100		
Output Low (Sink) Current I _{OL} Min.	0,4	0,5	5	0,64	0,61	0,42	0,36	0,51	1	—	mA	
	0,5	0,10	10	1,6	1,5	1,1	0,9	1,3	2,6	—		
	1,5	0,15	15	4,2	4	2,8	2,4	3,4	6,8	—		
Output High (Source) Current, I _{OH} Min.	4,6	0,5	5	-0,64	-0,61	-0,42	-0,36	-0,51	-1	—	mA	
	2,5	0,5	5	-2	-1,8	-1,3	-1,15	-1,6	-3,2	—		
	9,5	0,10	10	-1,6	-1,5	-1,1	-0,9	-1,3	-2,6	—		
	13,5	0,15	15	-4,2	-4	-2,8	-2,4	-3,4	-6,8	—		
Output Voltage: Low-Level, V _{OL} Max.	—	0,5	5	0,05				—	0	0,05	V	
	—	0,10	10	0,05				—	0	0,05		
	—	0,15	15	0,05				—	0	0,05		
Output Voltage: High-Level, V _{OH} Min.	—	0,5	5	4,95				4,95	5	—	V	
	—	0,10	10	9,95				9,95	10	—		
	—	0,15	15	14,95				14,95	15	—		
Input Low Voltage, V _{IL} Max.	0,5, 4,5	—	5	1,5				—	—	1,5	V	
	1,9	—	10	3				—	—	3		
	1,5, 13,5	—	15	4				—	—	4		
Input High Voltage, V _{IH} Min.	0,5, 4,5	—	5	3,5				3,5	—	—	V	
	1,9	—	10	7				7	—	—		
	1,5, 13,5	—	15	11				11	—	—		
Input Current I _{IN} Max.	—	0,18	18	±0,1	±0,1	±1	±1	—	±10 ⁻⁵	±0,1	μA	

CD4026B

When the DISPLAY ENABLE IN is low the seven decoded outputs are forced low regardless of the state of the counter. Activation of the display only when required results in significant power savings. This system also facilitates implementation of display-character multiplexing.

The CARRY OUT and UNGATED "C-SEGMENT" signals are not gated by the DISPLAY ENABLE and therefore are available continuously. This feature is a requirement in implementation of certain divider functions such as divide-by-60 and divide-by-12.

CD4033B

The CD4033B has provisions for automatic blanking of the non-significant zeros in a multi-digit decimal number which results in an easily readable display consistent with normal writing practice. For example, the number 0050.0700 in an eight digit display would be displayed as 50.07. Zero suppression on the integer side is obtained by connecting the RBI terminal of the CD4033B associated with the most significant digit in the display to a low-level voltage and connecting the RBO terminal of that stage to the RBI terminal of the CD4033B in the next-lower significant position in the display. This procedure is continued for each succeeding CD4033B on the integer side of the display.

On the fraction side of the display the RBI of the CD4033B associated with the least significant bit is connected to a low-level voltage and the RBO of that CD4033B is connected to the RBI terminal of the CD4033B in the next more-significant-bit position. Again, this procedure is continued for all CD4033B's on the fraction side of the display.

In a purely fractional number the zero immediately preceding the decimal point can be displayed by connecting the RBI of that stage to a high level voltage (instead of to the RBO of the next more-significant-stage). For example: optional zero → 0.7346. Likewise, the zero in a number such as 763.0 can be displayed by connecting the RBI of the CD4033B associated with it to a high-level voltage.

Ripple blanking of non-significant zeros provides an appreciable savings in display power.

The CD4033B has a LAMP TEST input which, when connected to a high-level voltage, overrides normal decoder operation and enables a check to be made on possible display malfunctions by putting the seven outputs in the high state.

The CD4026B- and CD4033B-series types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).

CD4026B, CD4033B Types

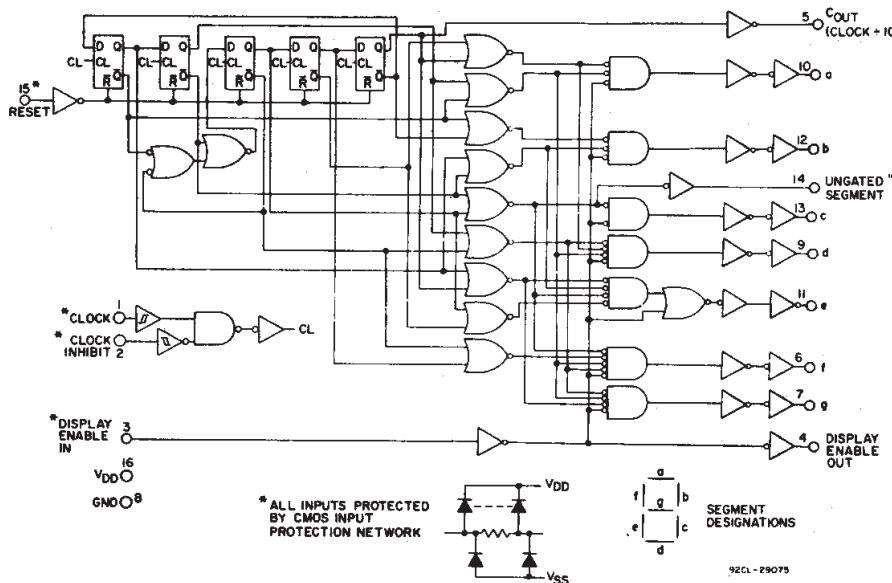


Fig. 1 – CD4026B logic diagram.

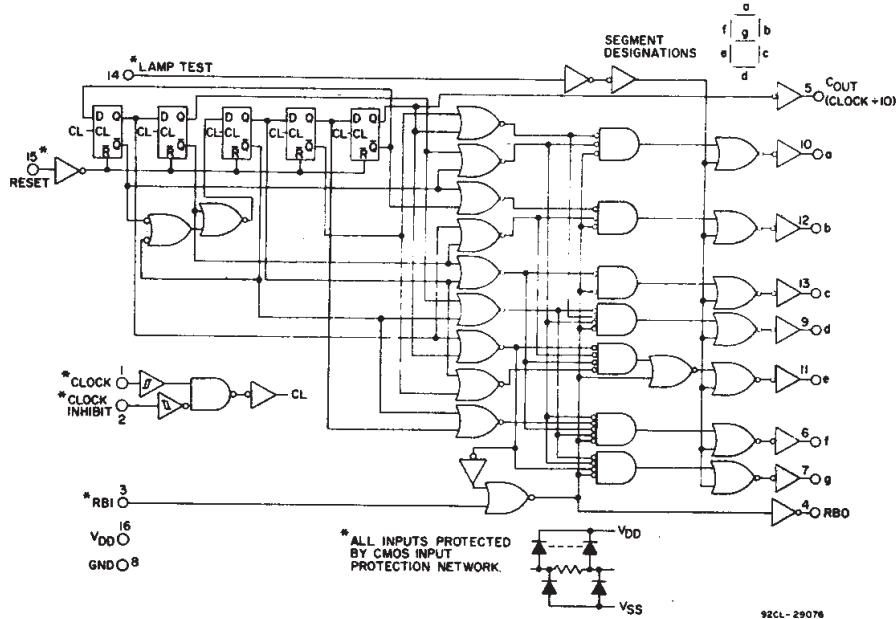


Fig. 2 – CD4033B logic diagram.

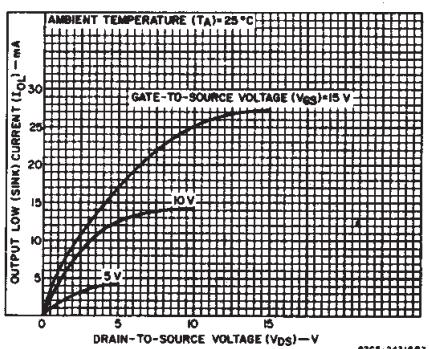


Fig. 6 – Typical n-channel output low (sink) current characteristics.

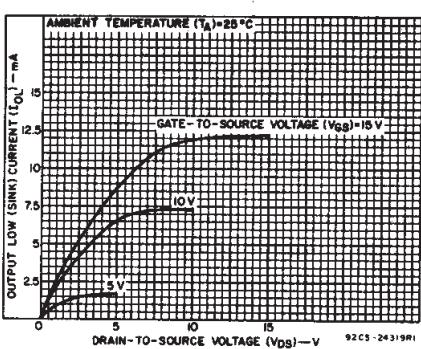


Fig. 7 – Minimum n-channel output low (sink) current characteristics.

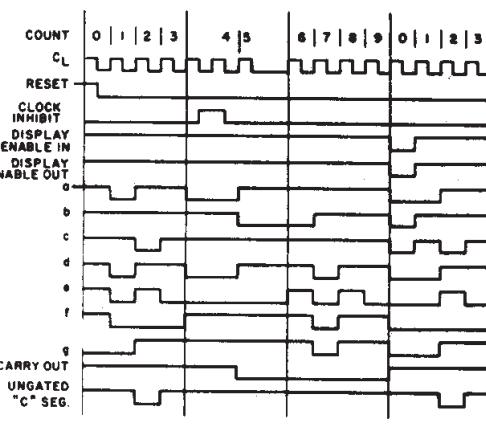


Fig. 3 – CD4026B timing diagram.

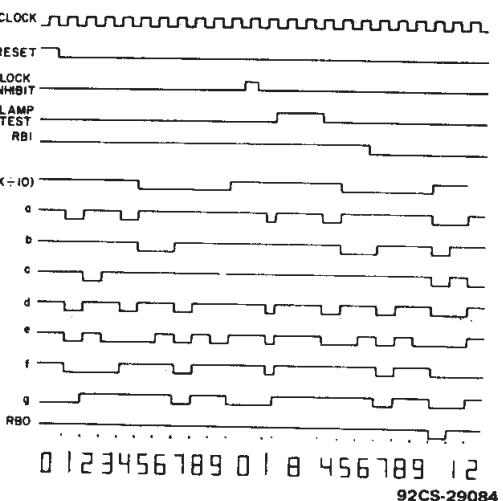


Fig. 4 – CD4033B timing diagram.

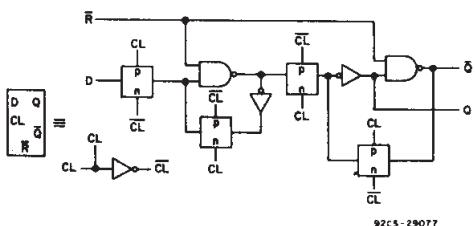


Fig. 5 – Detail of typical flip-flop stage for both types.

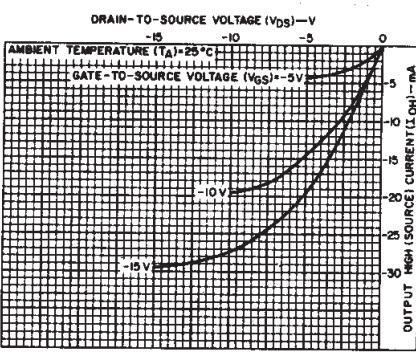


Fig. 8 – Typical p-channel output high (source) current characteristics.

CD4026B, CD4033B Types

DYNAMIC ELECTRICAL CHARACTERISTICS at $T_A = 25^\circ C$, Input $t_r, t_f = 20 \text{ ns}$,
 $C_L = 50 \text{ pF}, R_L = 200 \text{ k}\Omega$

CHARACTERISTIC	TEST CONDITIONS V_{DD} (V)	LIMITS			UNITS		
		Min.	Typ.	Max.			
CLOCKED OPERATION							
Propagation Delay Time; Carry-Out Line		5	—	250	500	ns	
		10	—	100	200		
		15	—	75	150		
Decode Outlines		5	—	350	700		
		10	—	125	250		
		15	—	90	180		
Transition Time; Carry-Out Line		5	—	100	200	MHz	
		10	—	50	100		
		15	—	25	50		
Maximum Clock Input Frequency, f_{CL}^Δ		5	2.5	5	—		
		10	5.5	11	—		
		15	8	16	—		
Min. Clock Pulse Width, t_W		5	—	110	220		
		10	—	50	100		
		15	—	40	80		
Clock and Clock Inhibit Rise or Fall Time; t_{rCL}, t_{fCL}		5	Unlimited			ns	
		10	Unlimited				
		15	Unlimited				
Average Input Capacitance, C_{IN}	Any Input	—	5	7	pF		
RESET OPERATION							
Propagation Delay Time; To Carry-Out Line, t_{PLH}		5	—	275	550	ns	
		10	—	120	240		
		15	—	80	160		
To Decode Out Lines, t_{PHL}, t_{PLH}		5	—	300	600		
		10	—	125	250		
		15	—	90	180		
Min. Reset Pulse Width, t_W		5	—	100	120		
		10	—	50	100		
		15	—	25	50		
Min. Reset Removal Time		5	—	0	30		
		10	—	0	15		
		15	—	0	10		

^Δ Measured with respect to carry-out line.

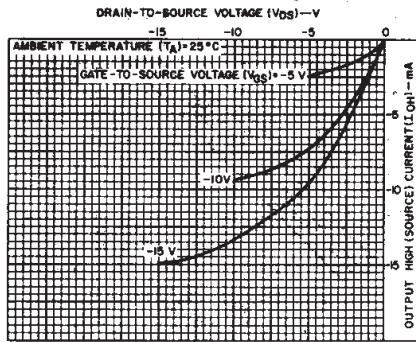


Fig. 9 – Minimum p-channel output high (source) current characteristics.

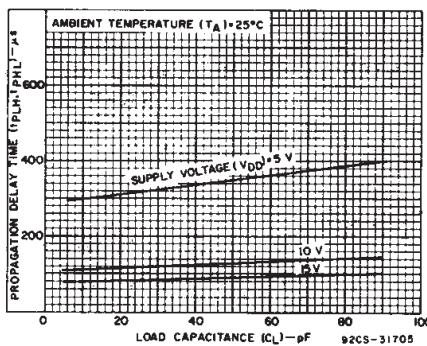


Fig. 10 – Typical propagation delay time as a function of load capacitance for decoded outputs.

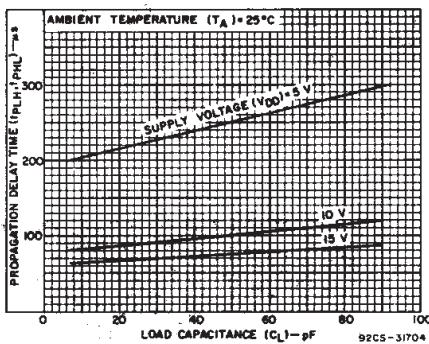


Fig. 11 – Typical propagation delay time as a function of load capacitance for carry-out outputs.

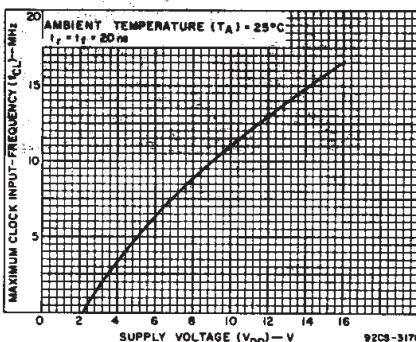


Fig. 12 – Typical maximum clock input-frequency as a function of supply voltage.

CD4026B, CD4033B Types

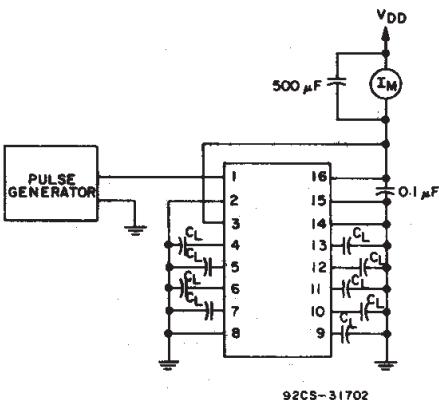
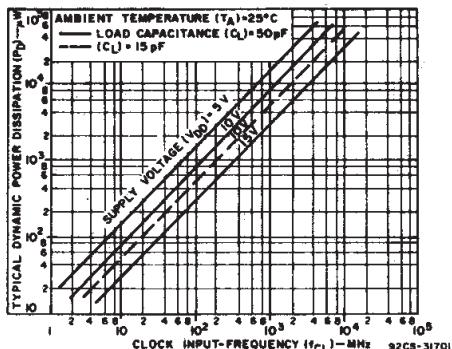


Fig. 14 – Dynamic power dissipation test circuit for CD4033B.

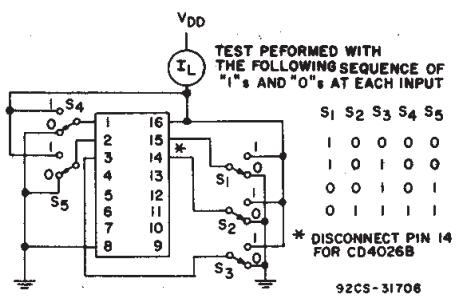


Fig. 15 – Quiescent device current.

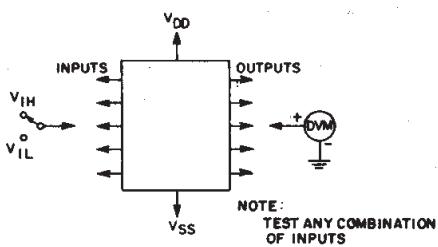


Fig. 16 – Input voltage.

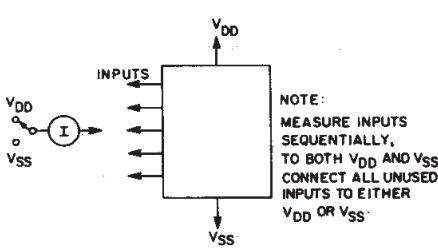
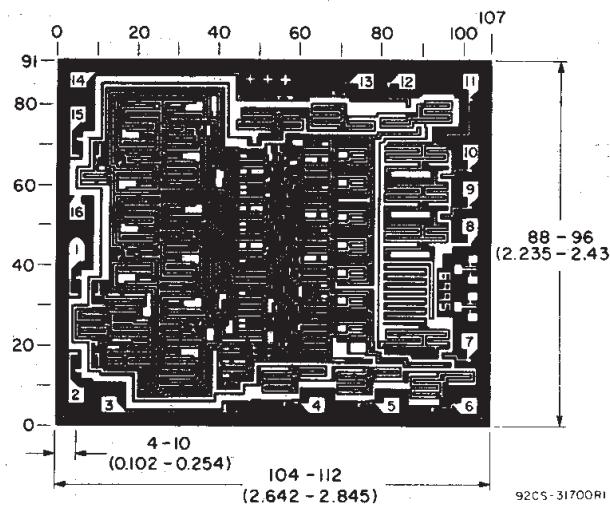
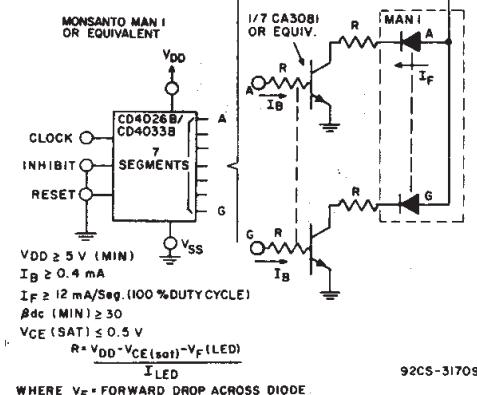
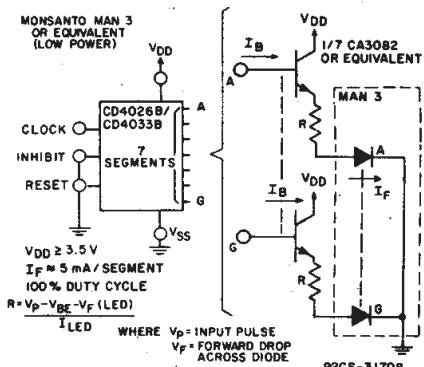


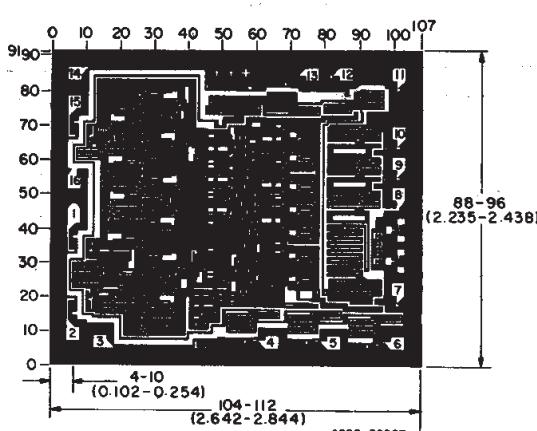
Fig. 17 – Input current.

INTERFACING THE CD4026B AND CD4033B WITH COMMERCIALLY AVAILABLE LIGHT EMITTING DIODE DISPLAYS

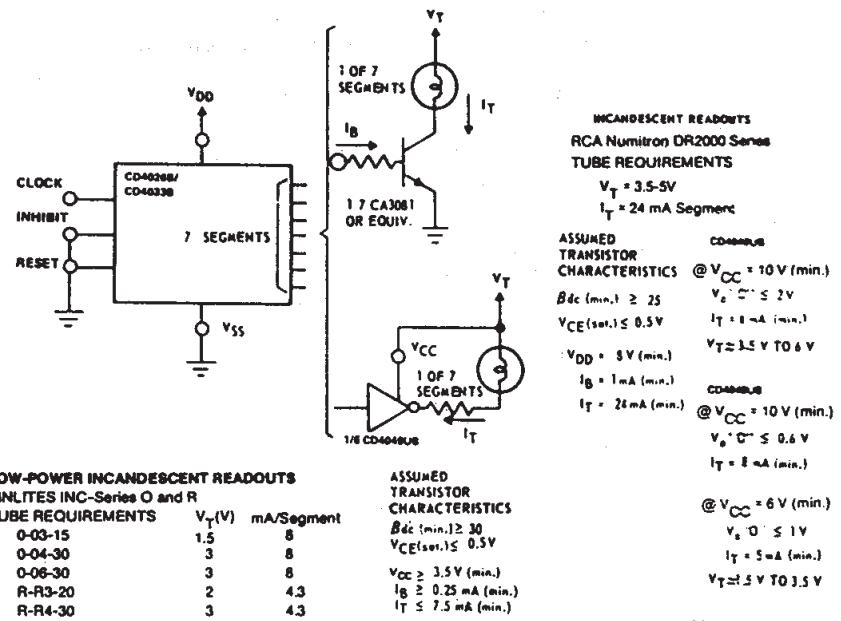


Chip dimensions and pad layout for CD4026B

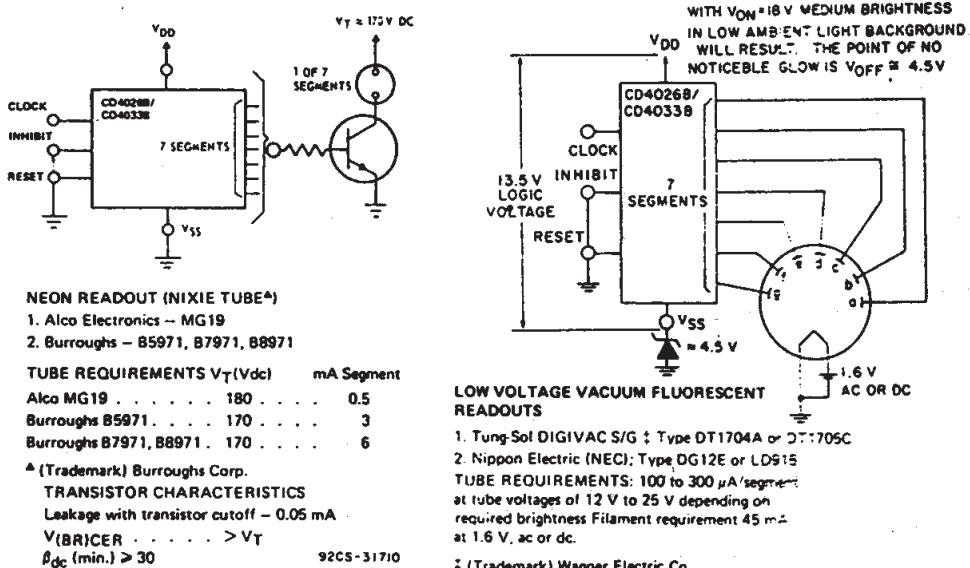
Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).



Chip dimensions and pad layout for CD4033B

CD4026B, CD4033B Types**INTERFACING THE CD4026B AND CD4033B WITH COMMERCIALLY AVAILABLE 7-SEGMENT DISPLAY DEVICES***

* The interfacing buffers shown, while a necessity with the CD4026A and CD4033A, are not required when using the "B" devices; the "B" outputs (≈ 10 times the "A" outputs) can drive most display devices directly especially at voltages above 10 V.



IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1999, Texas Instruments Incorporated